

AUTOMOTIVE GRADE

AUIRF1324S AUIRF1324L

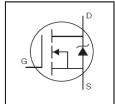
HEXFET® Power MOSFET

Features

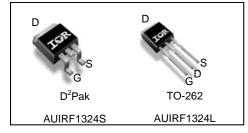
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- · Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



V _{DSS}	24V
R _{DS(on)} typ.	1.3mΩ
max.	1.65mΩ
D (Silicon Limited)	340A①
D (Package Limited)	195A



G	D	S
Gate	Drain	Source

Base nort number	Dookogo Typo	Standard Pack		Orderable Bort Number
Base part number	part number Package Type Form		Quantity	Orderable Part Number
AUIRF1324L	TO-262	Tube	50	AUIRF1324L
AUIRF1324S D²-Pak		Tube	50	AUIRF1324S
AUIRF1324S	D-Pak	Tape and Reel Left	800	AUIRF1324STRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	340	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	240	Δ.
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	195	А
I _{DM}	Pulsed Drain Current ②	1420	
P _D @T _C = 25°C	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 3	270	mJ
I _{AR}	Avalanche Current ②	See Fig.14,15, 18a, 18b	Α
E _{AR}	Repetitive Avalanche Energy ②		mJ
dv/dt	Peak Diode Recovery 4	0.46	V/ns
TJ	Operating Junction and	-55 to + 175	
T_{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	ol Parameter		Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.50	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount), D2 Pak®		40	C/VV

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	24			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		22		mV/°C	Reference to 25°C, I _D = 5mA ②
R _{DS(on)}	Static Drain-to-Source On-Resistance		1.3	1.65	mΩ	$V_{GS} = 10V, I_D = 195A$ ⑤
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Trans conductance	180			S	$V_{DS} = 10V, I_{D} = 195A$
R_G	Gate Resistance		2.3		Ω	
	Drain to Course Leakers Current			20		$V_{DS} = 24V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nΛ	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

			/		
Q_g	Total Gate Charge	 160	240		$I_D = 195A$
Q_{gs}	Gate-to-Source Charge	 84		0	$V_{DS} = 12V$
Q_{gd}	Gate-to-Drain Charge	 49		nC	V _{GS} = 10V⑤
Q_{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})	 76			
t _{d(on)}	Turn-On Delay Time	 17			$V_{DD} = 16V$
t _r	Rise Time	 190		no	$I_D = 195A$
t _{d(off)}	Turn-Off Delay Time	 83		ns	$R_G = 2.7\Omega$
t _f	Fall Time	 120			V _{GS} = 10V⑤
C _{iss}	Input Capacitance	 7590			$V_{GS} = 0V$
Coss	Output Capacitance	 3440			$V_{DS} = 24V$
C _{rss}	Reverse Transfer Capacitance	 1960		pF	f = 1.0MHz, See Fig. 5
Coss eff.(ER)	Effective Output Capacitance (Energy Related)	 4700		-	$V_{GS} = 0V$, $V_{DS} = 0V$ to $19V$
C _{oss eff.(TR)}	Effective Output Capacitance (Time Related)	 4490			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 19V$

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current			350①		MOSFET symbol
-5	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			1420		integral reverse
ISM	(Body Diode) ②			1420		p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25$ °C, $I_S = 195$ A, $V_{GS} = 0$ V (S)
4	Bayaraa Baaayary Tima	— 46 —			20	$T_{J} = 25^{\circ}C \qquad V_{DD} = 20V$
t _{rr}	Reverse Recovery Time		71		ns	$T_J = 125^{\circ}C$ $I_F = 195A$,
	Bayaraa Baaayary Charga		160		nC	$T_J = 25^{\circ}C$ di/dt = 100A/µs ©
Q_{rr}	Reverse Recovery Charge		430		IIC	$T_J = 125$ °C
I _{RRM}	Reverse Recovery Current		7.7		Α	T _J = 25°C
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 195A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- 3 Limited by T_{Jmax_s} starting $T_J = 25^{\circ}C$, L = 0.014mH, $R_G = 25\Omega$, $I_{AS} = 195$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.

- © Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- © C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



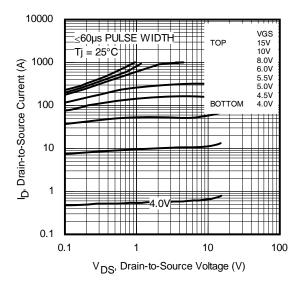


Fig. 1 Typical Output Characteristics

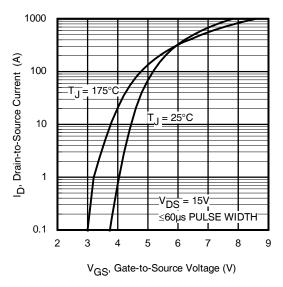


Fig. 3 Typical Transfer Characteristics

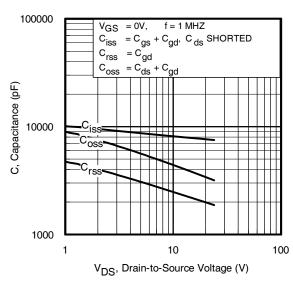


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

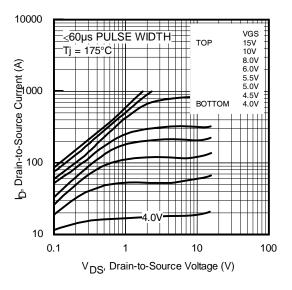


Fig. 2 Typical Output Characteristics

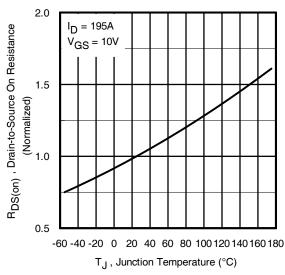


Fig. 4 Normalized On-Resistance vs. Temperature

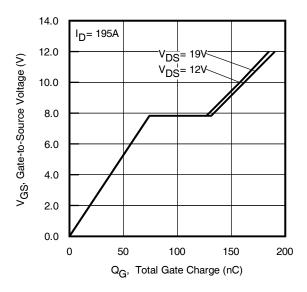


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



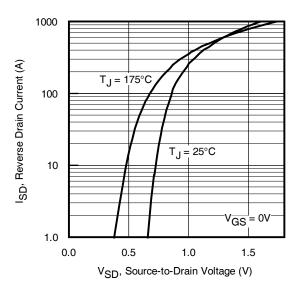


Fig. 7 Typical Source-to-Drain Diode Forward Voltage 350 300 imited By Package 250 Drain Current (A) 200 150 ڡٛ 100 50 0 150 175 25 50 75 100 125

Fig 9. Maximum Drain Current vs. Case Temperature

 T_C , Case Temperature (°C)

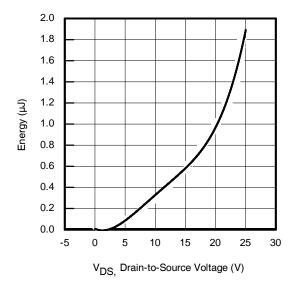


Fig 11. Typical Coss Stored Energy

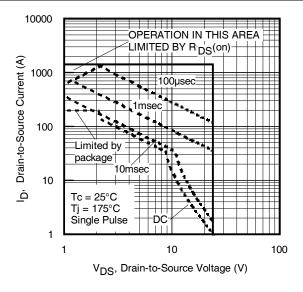


Fig 8. Maximum Safe Operating Area

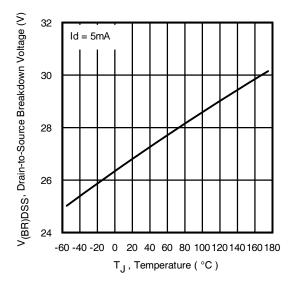


Fig 10. Drain-to-Source Breakdown Voltage

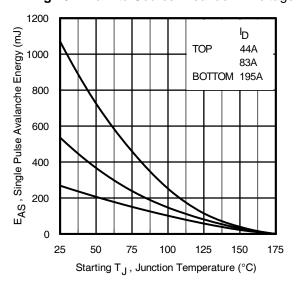


Fig 12. Maximum Avalanche Energy vs. Drain Current



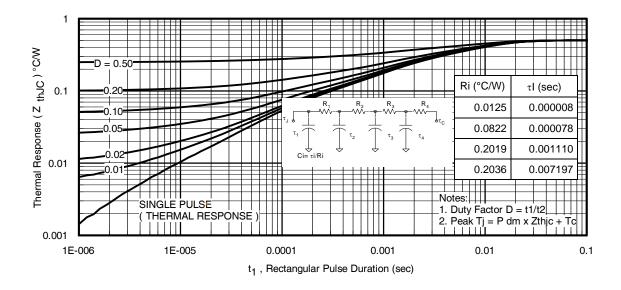


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

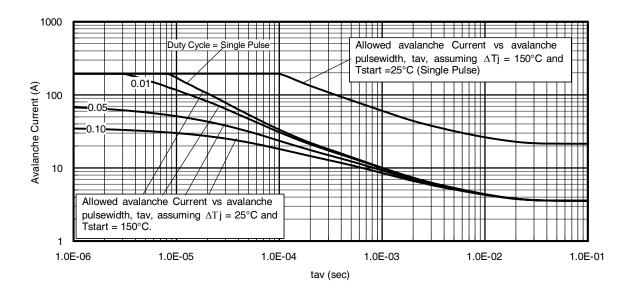
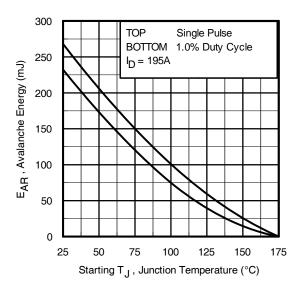


Fig 14. Avalanche Current vs. Pulse width





Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 18a, 18b.
- 1. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 13, 14).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{ Z}_{thJC} \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Z}_{th} \text{]} \\ &= E_{AS \text{ (AR)}} = P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

Fig 15. Maximum Avalanche Energy vs. Temperature

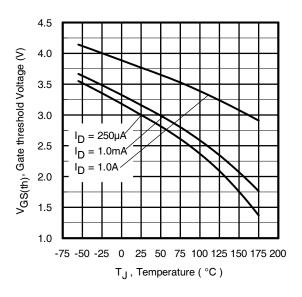


Fig 16. Threshold Voltage vs. Temperature



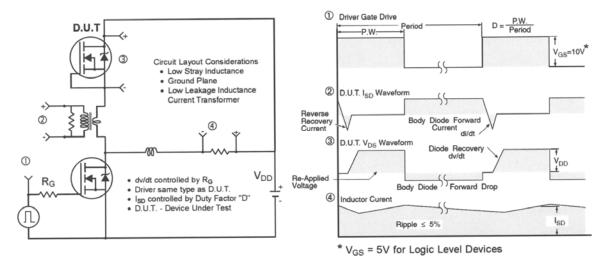


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

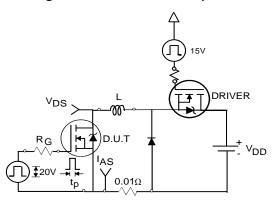


Fig 18a. Unclamped Inductive Test Circuit

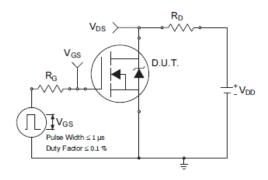


Fig 19a. Switching Time Test Circuit

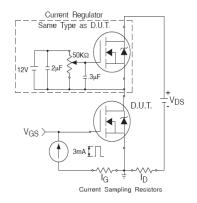


Fig 20a. Gate Charge Test Circuit

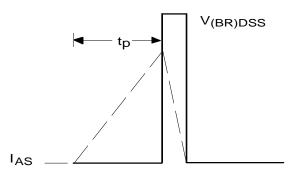


Fig 18b. Unclamped Inductive Waveforms

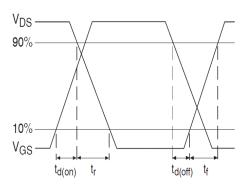


Fig 19b. Switching Time Waveforms

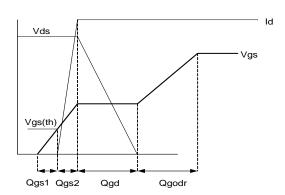
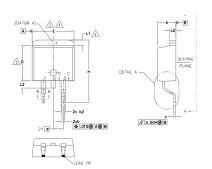
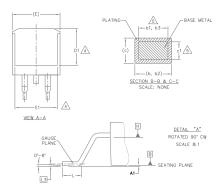


Fig 20b. Gate Charge Waveform



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S			N		
M B	MILLIM	ETERS	INC	HES	O T E S
0 L	MIN.	MAX.	MIN.	MAX.	S
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
Ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
ь3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

LEAD ASSIGNMENTS

DIODES

1.— ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.— CATHODE 3.— ANODE

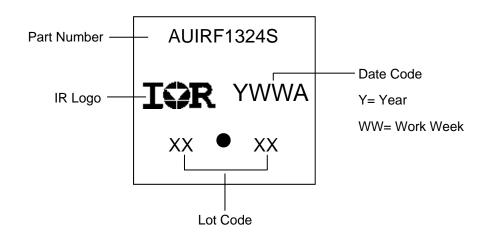
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

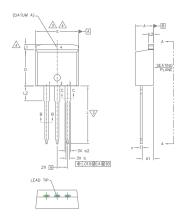
D²Pak (TO-263AB) Part Marking Information

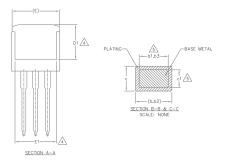


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED $^{\circ}$ 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE
 2.- COLLECTOR
 3.- EMITTER
 4.- COLLECTOR

HEXFET DIODES

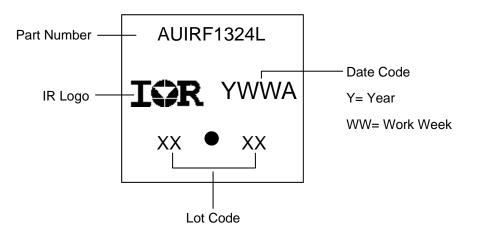
1.- ANODE (TWO DIE) / OPEN (ONE DIE) 1.- GATE

2.- DRAIN 3.- SOURCE 2, 4.- CATHODE 3.- ANODE

4.- DRAIN

S Y M		N				
В	MILLIM	MILLIMETERS		INCHES		
0 L	MIN.	MAX.	MIN.	MAX.	O T E S	
А	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
ь3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	_	.270	_	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245		4	
е	2.54	BSC	.100	BSC		
L	13.46	14.10	.530	.555		
L1	_	1.65	_	.065	4	
L2	3.56	3.71	.140	.146		

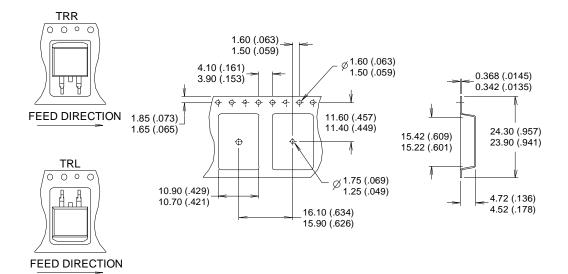
TO-262 Part Marking Information

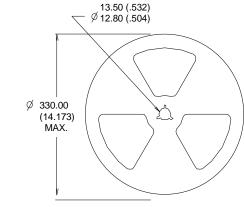


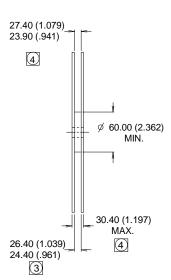
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- NOTES:
- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- ② INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

		Automotive (per AEC-Q101)				
Qualificati	Qualification Level		is part number(s) passed Automotive qualification. Infineon's			
		Industrial and C	consumer qualification level is granted by extension of the higher			
		Automotive leve	ol.			
Moisture Sensitivity Level		D ² -Pak	MSL1			
inolotal o	moisture deficiently Level		MOE!			
	Machine Model		Class M4 [†]			
	iviachine Model	AEC-Q101-002				
E0D	Lluca an Dadu Madal		Class H3A [†]			
ESD	Human Body Model	AEC-Q101-001				
	Channad Davisa Madal	Class C5 [†]				
	Charged Device Model		AEC-Q101-005			
RoHS Con	Compliant Yes					

[†] Highest passing voltage.

Revision History

Date	Comments
11/11/2015	Updated datasheet with corporate template
	Corrected ordering table on page 1.

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

IMPORTANT NOTICE

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.

单击下面可查看定价,库存,交付和生命周期等信息

>>Infineon Technologies(英飞凌)